X-ray monochromators

T. Matsushita Photon Factory High Energy Accelerator Research Organization

outline

- 1. Controlling X-ray beam properties and the roll of crystal monochromators
- 2. Bragg diffraction by crystals
- 3. Dynamical diffraction
- 4. Double crystal monochromator
- 5. Heat load and cooling
- 6. Higher harmonics rejection
- 7. High resolution monochromators
- 8. Phase retarder and polarization conversion
- 9. Curved crystals
- 10. Other issues and future problems

Winick: Presentation at JASS02 Seminar http://conference.kek.jp/JASS02/PDF_PPT/3_2_winick. ppt

Synchrotron Radiation - Basic Properties



- X-ray optical consideration -

EXAFS



Protein crystallography





λ : 0.7 Å ~ 3 Å (E : 18 keV ~4 keV) $\Delta \lambda / \lambda (\Delta E/E) : 10^{-3} ~ 10^{-4}$ Angular divergence : 2 ~ 0.2 mrad Beam spot size : 5 ~ 200 μm

E: ~4 keV - ~20 keV (~10 keV - ~50 keV) ∆E/E: ~10-4

Beam size: 1 mm x 10 mm – 1 μ m²

Designing your experiment - X-ray optical consideration -



Controlling the X-ray beam properties by X-ray crystal monochromators



Example of beamline structure @SPring-8



Lattice planes of silicon

Top view



a₀ = 5.43095 Å *d*-spacing (400) : 1.3578 Å

(111) : 3.1356 Å

(311) : 1.6375 Å

(511) : 1.0452 Å



Side view



Crystal monochromators

Bragg's law of difraction

$$2d(\text{\AA})\sin(\theta) = n\lambda(\text{\AA}) = n\frac{12.4}{E(keV)}$$

d: Latiice (d)-spacing,
 θ : glancing angle,
 λ : X-ray wavelength

10 keV : 1.24 Å, 1 Å : 12.4 keV

Energy (wavelength) resolution

$$\frac{\Delta E}{E} = \frac{\Delta \lambda}{\lambda} = \Delta \theta \cot \theta$$

Higher harmonics

$$E_1 = 10 \text{ keV} (n = 1)$$

 $E_2 = 20 \text{ keV} (n = 2)$
 $E_3 = 30 \text{ keV} (n = 3)$



Energy range of SPring-8 standard monochromator

e.g. For SPring-8 standard monochromator



Photon energy (wavelength) can be selected by crystal, net planes, and Bragg angle.

Preparation of crystal monochromator

No or less imperfections

dislocations stacking faults point defects (non-uniformly distributed, striations, aggregations)







Courtesy of Sharan Instruments Co. Ltd.

X-ray diffraction by a single crystal



X-Ray Dynamical Diffraction

- P. Ewald (1912, 1917): dipoles in the crystal which are excited by the incident X-ray wave and radiate X-rays.
- C. Darwin (1914): multiple reflection by lattice planes.
- M. von Laue (1931) : continuous medium consisting of periodic dielectric constant.
- Experimental proof: in 1960's and 1970's, big perfect crystals (silicon, germanium, etc) became available
- Since late 1970's, perfect crystals have been used as monochromators on synchrotron beamlines.

Textbooks and reviews

- B. W. Batterman and H. Cole, Rev. Mod. Phys. 36, 681 717 (1964) Dynamical Diffraction of X Rays by Perfect Crystals
- A. Authier, Dynamical Theory of X-Ray Diffraction, International Union of Crystallography Monographs on Crystallography No. 11. Oxford: Oxford University Press, 2001
- R. W. James: The Dynamical Theory of X-Ray Diffraction, in Solid State Physics (Seitz and Turnbull) vol.15 (1963), Academic Press
- M. von Laue: Roentgenstrahlen Interferenzen, 1941

Laue case and Bragg case



Laue case

K₀ K_h

 $F_{0r} = \sum_{j} f \exp(-ik r) \mathbf{Reflectivity}$

reflectivity for Bragg case, no absorption, and thick crystal:

$$R = \frac{|\gamma_{h}|}{\gamma_{0}} \left| \frac{E_{h}}{E_{0}} \right|^{2} = \left(W + \sqrt{W^{2} - 1} \right)^{2} \quad (W < -1)$$

$$R = 1 \quad (-1 \le W \le 1) \quad \leftarrow \text{ Total reflection}$$

$$R = \left(W - \sqrt{W^{2} - 1} \right)^{2} \quad (W > 1)$$
For symmetric Bragg case, sigma polarization:
$$W = \left\{ \Delta \theta \sin 2\theta_{BK} + \chi_{0r} \right\} \frac{1}{|\chi_{hr}|}$$
Darwin width $\Rightarrow \Delta W = 2$

$$\omega = \frac{2|\chi_{hr}|}{\sin 2\theta_{BK}} \propto |F_{h}|$$
Shift of Bragg angle due to refraction:
$$\Delta \theta_{refraction} = -\frac{\chi_{0r}}{\sin 2\theta_{BK}}$$

 $\gamma_{hr} = \frac{e^2 \lambda^2}{2} F_{hr} e^{-M}$

Silicon single crystal, E = 10 keV

hkl	Braqg angle (degree)	ω (arc sec)	ω (µrad)
111	11.403	5.476	26.55
220	18.836	3.984	19.32
311	22.246	2.273	11.02
400	27.167	2.495	12.10
422	34.001	1.886	9.142
333	36.379	1.228	5.952
440	40.22	1.543	7.479

 χ 0h on the web!!!

http://sergey.gmca.aps.anl.gov/x0h.html

For thick absorbing crystal in the Bragg-case (reflection geometry), the reflectivity is given by

$$R = L - \sqrt{L^{2} - (1 + 4\kappa^{2})}$$

$$L - \sqrt{(W^{2} - 1 - g^{2})^{2} + 4(gW - \kappa)^{2}} + W^{2} + g^{2}$$

$$\kappa = \frac{\chi_{hi}}{\chi_{h}r}$$

$$g = \frac{\chi_{0i}}{|\chi_{hr}|}$$

$$\kappa = \frac{\chi_{0i}}{|\chi_{hr}|}$$

For thin absorbing crystal of the Laue-case (transmission geometry), the reflectivity is given by

$$R_T = \frac{\exp(-\mu t / \gamma)}{(1 + W2)} \left[\sin^2 \left(A\sqrt{1 + W^2}\right) + \sinh^2 \frac{\kappa A}{\sqrt{1 + W^2}} \right]$$
$$A = \pi k \left| \chi_{hr} \right| t / \gamma$$



Intrinsic rocking curve for silicon

Based on the dynamical theory for perfect crystal

for thick crystal and absorption considered:



Features:

• Diffraction width (Darwin width) of $0.1 \sim 100 \mu rad$

Peak reflectivity of ~1 for low absorption case

Angular divergence of sources and diffraction width



Divergence of undulator radiation is the same order as diffraction width of low order reflection.

Energy resolution $\Delta E/E = 10^{-5} \sim 10^{-3}$





source-to-slit distance = 30 m

slit width = 1 mm

 $\Delta \theta = 3.3 \times 10^{-5}$

Si 111, 10 keV: $\theta = 11.4^{\circ}$

 $\Delta E/E = \Delta \theta \cot \theta = 1.6 \times 10^{-4}$

Energy resolution



SPring-8 standard DCM





 $3^{\circ} < \theta_{\rm B} < 27^{\circ}$ Offset *h*= 30 mm Adjustment stages

for undulator beamline DCM Sub-micron, sub-µrad control Goniometer and angle accuracy

Energy scan (Si 111 d = 3.119478 Å)

- E_0 : 10.000 keV $\theta = 11.46246^{\circ}$
- E_1 : 10.001 keV $\theta = 11.46130^{\circ}$

 $\Delta \theta = 0.001162^{\circ} = 4.18 \text{ arc s} = 20.3 \ \mu rad$







0.2 arc s / step (1 μrad / step)

Courtesy of Kohzu Seiki Co. Ltd.

Double crystal monochromator

 $h = 2g\cos(\theta)$

- Constant beam direction
- beam height changes slightly when E is changed.
- Two crystals should be parallel to each other within sub-arc-seconds.
- Tail intensity falls off rapidly.



NO

h

Alignment of a double crystal monochromator

(1) Parallelity in the scattering plane: sub-µrad



(2) Parallelity normal to the scattering plane: ~10⁻³ - 10⁻⁴ rad





Courtesy of Kohzu Seiki Co. Ltd.

Stability and disturbances

Variation at the sample

• Energy :

0.1 eV for XAFS, sub-meV for high resolution inelastic scattering

- Intensity : less than 1 %.
- Beam position: typically several tens ~ 1 μ m

Source instability

Source size change, source position change, charge distribution change

Room temperature variation

Heat load by the radiation itself

Vibration

floor, cooling water, vacuum pump

Fixed-exit DCM



A number of different schemes have been developed to realize a fixed-exit beam.

θ + two translation (KEK-PF)



PF BL-4C..

Matsushita et al., NIM A246 (1986)



h=25 mm, $\theta_{\rm B}=5\sim70^{\circ}$

Two cams for two translation-stages Rotation center at 2nd crystal

Heat load on 1st Crystal

Heat load on the mochromator 1st crystal:

→ For SPring-8 bending magnet source 100 W & 1 W/mm²

→ For SPring-8 standard undulator source ~500 W & ~ 500 W/mm²

cf.	Hot plate	: ~ 0.02 W/mm ²
	CPU	: ~ 0.3 W/mm²

Crystal cooling

Why crystal cooling?

- Qin (Heat load by SR) = Qout (Cooling + Radiation,..)
- \rightarrow with temperature rise ΔT
- $\rightarrow \alpha \Delta T = \Delta d$ (*d*-spacing change)
 - α : thermal expansion coefficient
- or $\rightarrow \varDelta \theta$ (bump of lattice due to heat load)

Miss-matching between 1st and 2nd crystals occurs:

- → Thermal drift, Loss of intensity, Broadening of beam, loss of brightness
- \rightarrow Melting or limit of thermal strain \rightarrow Broken !



Solution for crystal cooling

We must consider:

Thermal expansion of crystal: α , Thermal conductivity in crystal: κ , Heat transfer to coolant and crystal holder.

Solutions:

(S-1) κl α → Larger
(S-2) Large contact area between crystal and coolant/holder
→ larger
(S-3) Irradiation area → Larger, and power density → smaller

Figure of merit

	Silicon 300 K	Silicon 80 K	Diamond 300 K	Copper 300 K
<i>к</i> (W/m/K)	150	1000	2000	401
α (1/K)	2.5x10 ⁻⁶	-5x10 ⁻⁷	1x10 ⁻⁶	16.5x10 ⁻⁶
κ / α x10 ⁶	60	2000	2000	24

Figure of merit of cooling: Good for silicon (80 k) and diamond (300 K)

Liquid N₂: 77.36° K (-195.79° K)



Direct cooling with fin crystal

Improvement of fin-cooling crystal

Reduce radiation damage of rubber O-ring





Au-Si eutectic bonding

Direct cooling of silicon pin-post crystal + Rotated inclined geometry



Inclination angle $\beta = 80^{\circ}$

Grazing angle down to 1° using ϕ -rotation

Irradiation area enlarged to x50, power density reduced to 1/50

Applied to undulator beamline

Structure of pin-post crystal

Top plate with pin-post is bonded to base plate (manifold) using Au-Si eutectic bonding.



Performance of pin-post crystal



Rocking curve widths agree well.

A rocking curve is obtained by rocking (rotating) the second crystal of the double crystal arrangement and recording the diffracted intensity.

Cryogenic cooling

LN₂ circulator with He refrigerator



Applied to undulator beamline





Silicon, Liquid Nitrogen Cooling 465W, θ =6.9° 25 W/mm² Spring-8 undulator beamline

Temperature distribution



Deformation distribution

BL29XU LN2 cooled Si Crystal Deformation Analysis / Vertical direction



prepared for SRI2000,T. Mochizuki et.al, Cryogenic cooling monochromators for the SPring-8 undulator beamlines,

Coutecy of Dr. T. Mochizuki, Spring-8

prepared for SRI2000, T. Mochizuki et.al, Cryogenic cooling monochromators for the SPring-8 undulator beamlines,

Performance of pin-post cooling and cryogenic cooling

Heat load test (June 2000) up to 500 W, 500 W/mm²



Ila diamond indirect cooling

Merit:

- Good thermal properties \rightarrow Capability of indirect cooling
- Higher resolution ($\leftarrow \rightarrow$ Less throughput (30 \sim 40% of Si))

Issues:

- Perfection of crystal → HPHT IIa diamond (Sumitomo)...
 Successive upgrade is crucial !
- Holding of crystal \rightarrow X-ray topograph, Zygo
- Optimization of thermal contact \rightarrow New process with In insert
- Small crystal (< 10 mm[□])
- Alignment: using CCD camera, PIN photodiode, thermocouple

Topograph and rocking curve





Characterization of diamond monochromator Photon flux





 ε = 3 nm. rad, $I_{\rm b}$ = 100 mA Front-end slit aperture = 0.7 (v) x 1.0 (h) mm²

Low energy: 50~60% of Si DCM High energy: Infinite size effect ?

Improvement of crystal growth and surface finish is needed.



Higher harmonics rejection - Detuning of DCM -



e.g. $\Delta \theta$ = 12 µrad

- \rightarrow 70% of peak intensity for fundamental (111 refl. @ 10 keV)
- \rightarrow 0.3% of peak for 3rd harmonics (333 refl. @30 keV)

e.g. $\Delta \theta_2 = 10 \mu rad \rightarrow$ Angle change of exit beam = $2\Delta \theta_2 = 20 \mu rad$ Beam position change of 0.2 mm @10 m from DCM. We should recognize the beam position change by DCM detuning!

High resolution monochromator

double crystal arrangements and the DuMond diagram



Asymmetric diffraction for high resolution monochromator



Extremely High-Resolution X-Ray Monochromators





Alfred Q. R. Baron,a* Yoshikazu Tanaka,b Daisuke Ishikawa,b Daigo Miwa,b Makina Yabashia and Tetsuya Ishikawaa,b J. Synchrotron Rad. (2001). 8, 1127-1130



FIG. 1. Schematic top view of the experimental setup (a), and that of the intensity interferometer (b). The interferometer consists of a high-resolution monochromator using four separated crystals, a precision four-jaw slit, two semitransparent avalanche photodiodes (APDs), and coincidence circuits.



Spherical Diced Crystal Energy Analyzer







$$\frac{\Delta E}{E} = \sqrt{\omega^2 + \Delta \theta^2} \cot \theta$$

When $\theta = 89.97^\circ$
 $\cot \theta \sim 5.2 \ge 10^{-4}$

If $\sqrt{\omega^2 + \Delta \theta^2} \sim 10^{-3} - 10^{-4}$ $\Delta E/E \sim 10^{-7} - 10^{-8}$



R=9.8 m Spherical Diced Crystal Analyzer

Power Load Effects on Backscattering Monochromator





phase retarder, polarization conversion - transmission through a thin crystal -



Concept of dispersion surfaces should be utilized to understand.

M. Suzuki and T. Hirono, Hoshako(放射光) Nov. 2006, Vo.19 No6, pp.444-453

Sagittal focusing



q: crystal ~ focal point distance

Crystal~focal point= 16.5 m

R = 8 m

R = 6 m

R = 4 m

 \geq

Applied for bending magnet beamline

Dispersive X-ray Absorption Spectroscopy

T. Matsushita & R. P. Phizackerley:

Jpn. J. Appl. Phys. 20, 2223-2228 (1981)



Multiwavelength Dispersive X-Ray Reflectometry







Other issues

- Phase space analysis
 position-angle (position-momentum) space
- Extended Phase space position-angle-wavelength space position-angle-energy space
- Ray tracing
- Feedback control of the DCM
- Compton scattering (heating of the 2nd crystal)
- Stress due to crystal mounting
- Surface finish and residual stress layer
- Wide band-pass monochromators
- Quick-scan monochromators
- Dispersion surface

Future subjects

- Smaller slope error, smaller roughness, smaller residual stress
- optics for handling more coherent X-rays
- More higher resolution
- Wide bandpass crystal monochromator
- optics for handling more bright(intense) beam
- optics for handling extremely short pulses

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